# Contents

**Abstract** **v**

**Preface** **vii**

**Acknowledgements** **ix**

**Dedication** **xiii**

**1 Introduction** **1**

1.1 Wafersort . . . . . 1

1.2 Other Work . . . . . 6

1.3 Organization of the Dissertation . . . . . 8

1.4 Contributions . . . . . 10

**2 Pattern Characterization** **13**

2.1 Silicon Wafer Fabrication . . . . . 13

2.1.1 A Look at Wafer Layers . . . . . 14

2.1.2 Failure Patterns—A Motivation . . . . . 18

2.2 Choosing Pattern Shapes . . . . . 21

**3 Generating Objects at Random** **27**

3.1 Fundamentals of Statistical Pattern Generation . . . . . 27

3.2 Segment pdf's . . . . . 30

3.3 Band pdf's . . . . . 33

3.4 Disk pdf's . . . 38
3.4.1 Applying Constraints . . . 41
3.4.2 The pdf . . . 44
3.5 Annulus pdf's . . . 46
3.6 Ring pdf's . . . 48

**4 Calculating Feature Variables** **59**
4.1 Feature Concepts . . . 60
4.2 Segment Variables . . . 62
4.3 Band Variables . . . 66
4.4 A-Disk Variables . . . 71
4.5 B-Disk Variables . . . 74
4.6 A-Annulus Variables . . . 84
4.7 B-Annulus Variables . . . 90
4.8 A-Ring Variables . . . 93
4.9 B-Ring Variables . . . 97
4.10 C-Ring Variables . . . 106

**5 Synthesizing Wafer Maps with** Wafgen **113**
5.1 Generating and Re-classifying Discrete Maps . . . 114
5.1.1 Creating a Wafer Map at Random . . . 116
5.1.2 Rejecting Extreme Patterns . . . 116
5.1.3 Discretizing the Continuous Map . . . 117
5.1.4 Updating the Label . . . 118
5.2 A Comparison of Output with Theory . . . 119
5.2.1 A-Disk Area . . . 121
5.2.2 A-Annulus Area . . . 122
5.2.3 A-Ring Area . . . 124
5.2.4 Segment Area . . . 125
5.2.5 Band Area . . . 127

5.2.6 Conclusion . . . . . 128

**6 Standardizing Wafer Map Data** **129**

6.1 Overview . . . . . 130

6.2 Circumscribing the Smallest Enclosing Circle . . . . . 132

6.3 Splitting Raw Wafer Maps . . . . . 137

6.4 Calculating Initial Standard Values . . . . . 141

6.5 Correcting for Poor Coverage . . . . . 145

6.6 Thresholding the Standardized Splits . . . . . 146

6.7 Fine Features are Lost . . . . . 149

**7 Wafer Map Classification** **151**

7.1 Choosing Feature Categories . . . . . 152

7.1.1 Area . . . . . 153

7.1.2 Orientation . . . . . 158

7.1.3 Location . . . . . 159

7.1.4 Curve-Direction . . . . . 165

7.1.5 Counting Feature Combinations . . . . . 168

7.2 An Introduction to Classification . . . . . 169

7.2.1 Prototype Classification . . . . . 171

7.2.2 Nearest Neighbor Classification . . . . . 173

7.3 On Bayes Classification . . . . . 174

7.3.1 The optimal classifier . . . . . 176

7.3.2 A prototype classifier . . . . . 176

7.3.3 A feature classifier . . . . . 177

7.4 Making Datasets . . . . . 180

7.4.1 Making Prototypes . . . . . 181

7.4.2 Making Neighbor Sets . . . . . 184

7.4.3 Making Synthetic Input Sets . . . . . 188

**8 Studies with Synthetic Wafer Maps** **191**

8.1 A Bound on the Bayes Error Rate . . . 192

8.1.1 Method . . . 194

8.1.2 Results . . . 194

8.1.3 Summary . . . 198

8.2 Classifying Perfect Wafer Maps . . . 199

8.2.1 Method . . . 199

8.2.2 Confusion Matrices . . . 200

8.2.3 Results: Shape Confusions . . . 202

8.2.4 Results: Area Confusions . . . 206

8.2.5 Results: Location Confusions . . . 212

8.2.6 Results: Orientation Confusions . . . 216

8.2.7 Results: Curve Direction Confusions . . . 219

8.2.8 Discussion . . . 221

8.3 Classifying Noisy Wafer Maps . . . 222

8.3.1 Method . . . 223

8.3.2 General Results . . . 225

8.3.3 Noise Results: Shape . . . 230

8.3.4 Noise Results: Area . . . 230

8.3.5 Noise Results: Location . . . 233

8.3.6 Discussion . . . 235

8.4 A Theoretical Model of Noise Performance . . . 237

8.4.1 A One-Map Model . . . 237

8.4.2 A Two-Map Model . . . 239

8.4.3 Applying the Models . . . 241

**9 Studies with Real Wafer Maps** **247**

9.1 A Dataset with Real Wafer Maps . . . 249

9.2 Perfecting Industrial Wafer Maps . . . 253

9.2.1 Filling in Bit Noise—Dataset `DFIL` . . . 254

9.2.2 Removing Tiny Clusters—Dataset DCFM . . . 254
9.2.3 Making the Perfected Map—Dataset DPRF . . . 255
9.3 An Analysis of Noise in Industrial Maps . . . 256
9.3.1 Datasets . . . 258
9.3.2 Analysis of Noise . . . 261
9.4 Classifying Real Wafer Maps . . . 261
9.4.1 Results . . . 263
9.5 Data as Classifier: Explorations . . . 264
9.6 Using Data to Classify Data . . . 266
9.6.1 Datasets . . . 267
9.6.2 General Results . . . 268
9.6.3 Results by Feature . . . 271
9.6.4 Conclusions . . . 279
9.7 Data Classifies Perfect Maps + Noise . . . 279
9.7.1 Method . . . 280
9.7.2 Results . . . 281
9.7.3 Conclusions . . . 284
9.8 Decomposition of Classifier Error . . . 285
9.8.1 Discussion . . . 288
9.9 Bit Noise is Clustered in DATA . . . 289
9.9.1 Method . . . 289
9.9.2 Results . . . 291
9.10 Measuring a Database . . . 295
9.10.1 Pdf's of $\theta$ . . . 295
9.10.2 Pdf's of $b$ . . . 297
9.10.3 Pdf's of $r$ . . . 299
9.10.4 Conclusions . . . 300

**10 Conclusions and Future Work** **301**

10.1 Contributions . . . 302

10.2 Future Work . . . . . 304

**A Bertrand's Paradox** **307**

A.1 The Paradox . . . . . 308

A.2 Clarification . . . . . 309

A.2.1 Solution #1 . . . . . 309

A.2.2 Solution #2 . . . . . 311

A.2.3 Solution #3 . . . . . 312

A.3 Resolution . . . . . 312

**B Calculating Orientation** **315**

B.1 The Orientation of a Set of Points on a Grid . . . . . 315

B.2 Derivation . . . . . 316

B.3 Solutions . . . . . 320

B.3.1 Case 1: $S_{xy} = 0$ . . . . . 320

B.3.2 Case 2: $S_{xy} \neq 0$ . . . . . 321

B.4 Solutions for Wafer Map Orientation . . . . . 322

**C Details of Standardization** **325**

C.1 Wafer Maps as Formats and with Devices . . . . . 325

C.2 Fitting the Smallest Enclosing Circle . . . . . 332

C.3 Overlapping Raw and Standard Wafer Maps . . . . . 340

**D Tables of Wafer Map Classes** **347**

D.1 Introduction . . . . . 347

D.2 One-Zone Prototypes . . . . . 348

D.3 Two-Zone Prototypes . . . . . 349

D.4 Three-Zone Prototypes . . . . . 352

D.5 Sample Prototypes . . . . . 356

**E Prior Probabilities of Datasets** **359**

E.1 Adjacency figures for Three-Zone Shapes . . . . . 359

E.2 Priors of the Theoretical Uniform Distribution . . . . . 360
E.2.1 Theoretical Area Priors . . . . . 360
E.2.2 Theoretical Orientation Priors . . . . . 360
E.2.3 Theoretical Location Priors . . . . . 360
E.2.4 Theoretical Curvature Priors . . . . . 361
E.3 Priors for the Input Datasets . . . . . 367
E.4 Priors for Neighbor and Prototype Datasets . . . . . 367

**F Details of the Noise Models** **381**
F.1 The One-Map Model . . . . . 381
F.2 The Two-Map Model . . . . . 385
F.2.1 Three Proofs . . . . . 388
F.2.2 Derivation . . . . . 389
F.3 Further Model Developments . . . . . 392
F.4 Graphs and Tables . . . . . 393

**Bibliography** **405**